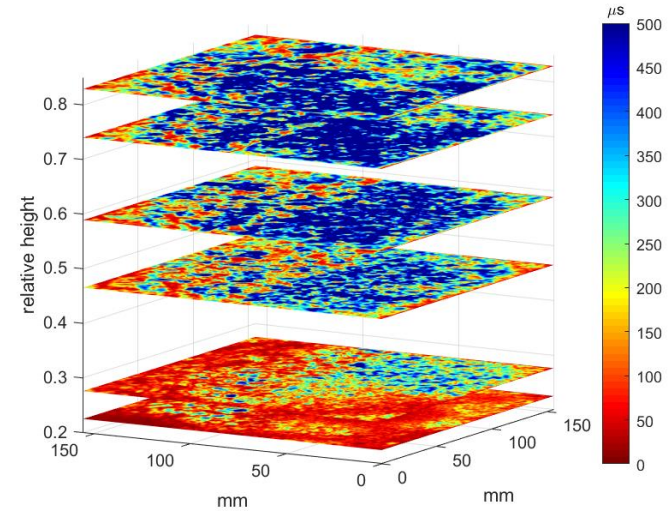
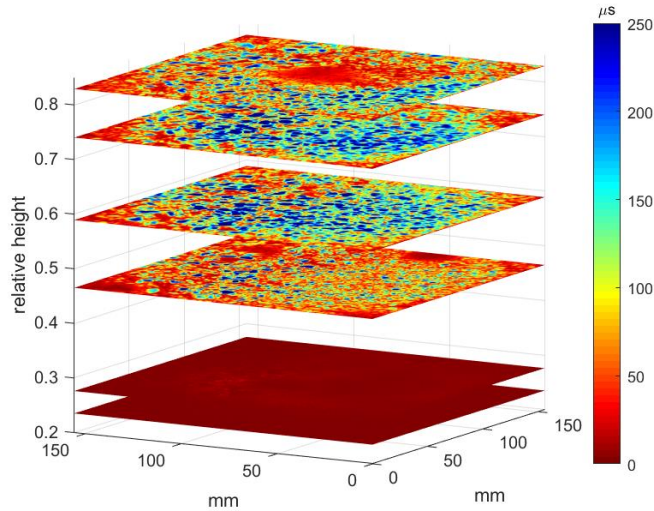


*Material quality
investigation of high
performance multicrystalline
silicon by carrier lifetime
measurements*

Ida Due-Sørensen

Lifetime characterization

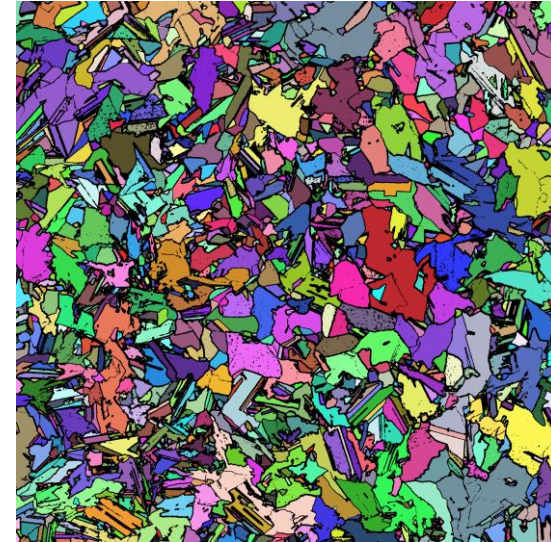
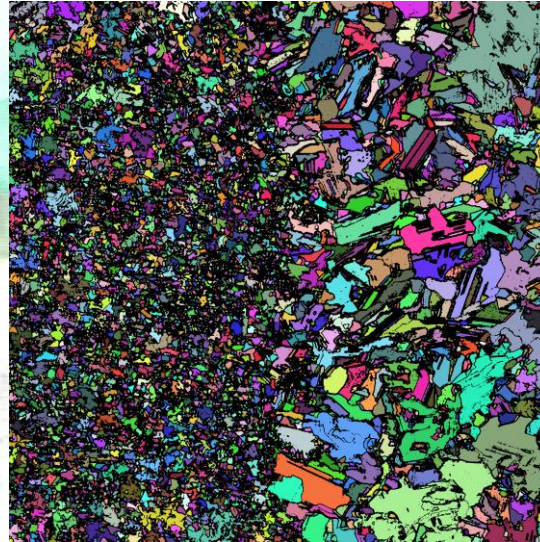
» As-cut vs. gettered and hydrogenated wafers





Structural characterization

- » Wafers from ~20 and 83 % of ingot height.





Summary

Aim:

- Assess the effect of seeding on grain structure and lifetime.

General trends:

- Gettering and hydrogenation improves lifetimes.
- Small grains are favorable for this ingot, especially for PDGH wafers.

Experimental:

- Lifetime characterization.
- Grain structure.